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Sensing for In-Process Monitoring of High-Value Manufacturing Processes

Guest Editors:

Prof. Ashutosh Tiwari
a.tiwari@sheffield.ac.uk

Prof. Geraint Jewell
g.jewell@sheffield.ac.uk

Dr. Divya Tiwari
d.tiwari@sheffield.ac.uk

Dr. Michael Farnsworth
m.j.farnsworth@sheffield.ac.uk

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Message from the Guest Editors

This Special Issue aims to bring together research relating to sensing for in-process monitoring of high-value manufacturing processes. We invite you to contribute to this issue by submitting both case studies and research articles focusing on high-value manufacturing processes. This Special Issue will cover papers from a range of manufacturing processes including (but not limited to): surface manufacturing, machining, assembly, and continuous manufacturing. We particularly welcome papers from high-value manufacturing application areas, such as electrical machine manufacture, aerostructure assembly, and surface manufacture.



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